

1 IN THE CLAIMS:

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3 Please amend claims 1, 54, and 61 as follows:

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5 1. A method of using Si-Ge-C in selective etch applications, comprising:
6 growing one or more layers on a single crystal silicon substrate, at least one of
7 which is a Si-Ge-C layer, wherein the carbon of the Si-Ge-C layer is an amount from 1
8 to 10 atomic percent and sufficient to exhibit etch selectivity with respect to the single
9 crystal silicon substrate and/or one or more of the epitaxial layers adjacent the Si-Ge-C
10 layer; and

11 etching with a liquid etchant, the Si-Ge-C layer and the single crystal silicon
12 substrate and/or one or more of the epitaxial layers adjacent the Si-Ge-C layer.

13 54. A method of using Si-Ge-C in selective etch applications in conjunction with
14 a single crystal substrate, comprising:

15 growing one or more epitaxial layers sequentially, starting at the single crystal
16 substrate surface, wherein at least one of the epitaxial layers comprises Si-Ge-C,
17 wherein the carbon of the Si-Ge-C layer is [up] from 1 to 5 atomic percent; and
18 etching with a liquid etchant, the Si-Ge-C layer[,] and the single crystal substrate
19 and/or one or more of the epitaxial layers adjacent the Si-Ge-C layer.

21 61. A method of using Si-Ge-C in selective etch applications in conjunction with
22 a substrate, comprising:

23 growing one or more layers sequentially, starting at the substrate, wherein at
24 least one of the layers comprises Si-Ge-C, wherein the carbon of the Si-Ge-C layer is
25 [up] from 1 to 10 atomic percent; and

26 etching with a liquid etchant, the Si-Ge-C layer and one or more layers adjacent
27 to the Si-Ge-C layer and/or the substrate.

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1 A clean copy of claims 1, 54, and 61 is as follows:

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3 1. A method of using Si-Ge-C in selective etch applications, comprising:
4 growing one or more layers on a single crystal silicon substrate, at least one of
5 which is a Si-Ge-C layer, wherein the carbon of the Si-Ge-C layer is an amount from 1
6 to 10 atomic percent and sufficient to exhibit etch selectivity with respect to the single
7 crystal silicon substrate and/or one or more of the epitaxial layers adjacent the Si-Ge-C
8 layer; and
9 etching with a liquid etchant, the Si-Ge-C layer and the single crystal silicon
10 substrate and/or one or more of the epitaxial layers adjacent the Si-Ge-C layer.

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12 54. A method of using Si-Ge-C in selective etch applications in conjunction with
13 a single crystal substrate, comprising:
14 growing one or more epitaxial layers sequentially, starting at the single crystal
15 substrate surface, wherein at least one of the epitaxial layers comprises Si-Ge-C,
16 wherein the carbon of the Si-Ge-C layer is from 1 to 5 atomic percent; and
17 etching with a liquid etchant, the Si-Ge-C layer and the single crystal substrate
18 and/or one or more of the epitaxial layers adjacent the Si-Ge-C layer.

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20 61. A method of using Si-Ge-C in selective etch applications in conjunction with
21 a substrate, comprising:
22 growing one or more layers sequentially, starting at the substrate, wherein at
23 least one of the layers comprises Si-Ge-C, wherein the carbon of the Si-Ge-C layer is
24 from 1 to 10 atomic percent; and
25 etching with a liquid etchant, the Si-Ge-C layer and one or more layers adjacent
26 to the Si-Ge-C layer and/or the substrate.

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1 Please add new claims 68-73 as follows:

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3 --68. A method of using Si-Ge-C in selective etch applications, comprising:
4 growing one or more layers on a single crystal silicon substrate, at least one of
5 which is a Si-Ge-C layer, wherein the carbon of the Si-Ge-C layer is sufficient to exhibit
6 etch selectivity with respect to the single crystal silicon substrate and/or one or more of
7 the epitaxial layers adjacent the Si-Ge-C layer; and
8 etching with a liquid etchant, the Si-Ge-C layer and the single crystal silicon
9 substrate and/or one or more of the epitaxial layers adjacent the Si-Ge-C layer wherein
10 the Si-Ge-C layer etches slower than the one or more adjacent epitaxial layers.

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12 69. A method of using Si-Ge-C in selective etch applications, comprising:
13 growing one or more layers on a single crystal silicon substrate, at least one of
14 which is a Si-Ge-C layer, wherein the carbon of the Si-Ge-C layer is sufficient to exhibit
15 etch selectivity with respect to the single crystal silicon substrate and/or one or more of
16 the epitaxial layers adjacent the Si-Ge-C layer; and
17 etching with a liquid etchant, the Si-Ge-C layer and the single crystal silicon
18 substrate and/or one or more of the epitaxial layers adjacent the Si-Ge-C layer wherein
19 the Si-Ge-C layer etches faster than the one or more adjacent epitaxial layers.

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21 70. A method of using Si-Ge-C in selective etch applications in conjunction with
22 a single crystal substrate, comprising:

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24 growing one or more epitaxial layers sequentially, starting at the single crystal
25 substrate surface, wherein at least one of the epitaxial layers comprises Si-Ge-C,
26 wherein the carbon of the Si-Ge-C layer is up to 5 atomic percent; and

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28 etching with a liquid etchant, the Si-Ge-C layer and the single crystal substrate
29 and/or one or more of the epitaxial layers adjacent the Si-Ge-C layer wherein the Si-Ge-
30 C layer etches slower than the one or more adjacent epitaxial layers.

1 71. A method of using Si-Ge-C in selective etch applications in conjunction with
2 a single crystal substrate, comprising:

3 growing one or more epitaxial layers sequentially, starting at the single crystal
4 substrate surface, wherein at least one of the epitaxial layers comprises Si-Ge-C,
5 wherein the carbon of the Si-Ge-C layer is up to 5 atomic percent; and

6 etching with a liquid etchant, the Si-Ge-C layer and the single crystal substrate
7 and/or one or more of the epitaxial layers adjacent the Si-Ge-C layer wherein the Si-Ge-
8 C layer etches faster than the one or more adjacent epitaxial layers.

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10 72. A method of using Si-Ge-C in selective etch applications in conjunction with
11 a substrate, comprising:

12 growing one or more layers sequentially, starting at the substrate, wherein at
13 least one of the layers comprises Si-Ge-C, wherein the carbon of the Si-Ge-C layer is
14 up to 10 atomic percent; and

15 etching with a liquid etchant, the Si-Ge-C layer and one or more layers adjacent
16 to the Si-Ge-C layer and/or the substrate wherein the Si-Ge-C layer etches slower than
17 the one or more adjacent layers.

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19 73. A method of using Si-Ge-C in selective etch applications in conjunction with
20 a substrate, comprising:

21 growing one or more layers sequentially, starting at the substrate, wherein at
22 least one of the layers comprises Si-Ge-C, wherein the carbon of the Si-Ge-C layer is
23 up to 10 atomic percent; and

24 etching with a liquid etchant, the Si-Ge-C layer and one or more layers adjacent
25 to the Si-Ge-C layer and/or the substrate wherein the Si-Ge-C layer etches faster than
26 the one or more adjacent layers.--

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